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Irish Standard  
I.S. EN 61988-5:2009

## Plasma display panels -- Part 5: Generic specification (IEC 61988-5:2009 (EQV))

## I.S. EN 61988-5:2009

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**Plasma display panels -  
Part 5: Generic specification  
(IEC 61988-5:2009)**

Panneaux d'affichage à plasma -  
Partie 5: Spécification générique  
(CEI 61988-5:2009)

Plasmabildschirme -  
Teil 5: Fachgrundspezifikation  
(IEC 61988-5:2009)

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Central Secretariat: Avenue Marnix 17, B - 1000 Brussels**

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## **Foreword**

The text of document 110/182/FDIS, future edition 1 of IEC 61988-5, prepared by IEC TC 110, Flat panel display devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61988-5 on 2009-12-01

The following dates were fixed:

- latest date by which the EN has to be implemented  
at national level by publication of an identical  
national standard or by endorsement (dop) 2010-09-01
- latest date by which the national standards conflicting  
with the EN have to be withdrawn (dow) 2012-12-01

Annex ZA has been added by CENELEC.

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## **Endorsement notice**

The text of the International Standard IEC 61988-5:2009 was approved by CENELEC as a European Standard without any modification.

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## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60027	Series	Letter symbols to be used in electrical technology	EN 60027	Series
IEC 60050	Series	International electrotechnical vocabulary	-	-
IEC 60410	1973	Sampling plans and procedures for inspection - by attributes	-	-
IEC 60617	Data-base	Graphical symbols for diagrams	-	-
IEC 60747-1	- <sup>1)</sup>	Semiconductor devices - Part 1: General	-	-
IEC 61988-1	- <sup>1)</sup>	Plasma display panels - Part 1: Terminology and letter symbols	EN 61988-1	2003 <sup>2)</sup>
IEC 61988-2-1	- <sup>1)</sup>	Plasma display panels - Part 2-1: Measuring methods - Optical	EN 61988-2-1	2002 <sup>2)</sup>
IEC 61988-2-2	- <sup>1)</sup>	Plasma display panels - Part 2-2: Measuring methods - Optoelectrical	EN 61988-2-2	2003 <sup>2)</sup>
IEC 61988-3-1	- <sup>1)</sup>	Plasma display panels - Part 3-1: Mechanical interface	EN 61988-3-1	2005 <sup>2)</sup>
IEC 61988-4	- <sup>1)</sup>	Plasma display Panels - Part 4: Climatic and mechanical testing methods	EN 61988-4	2007 <sup>2)</sup>
IECQ 01	- <sup>1)</sup>	IEC Quality Assessment System for Electronic Components (IECQ) - Basic Rules	-	-
IEC QC 001002	Series	IEC quality assessment system for electronic components (IECQ) - Rules of procedure	-	-
ISO 1000	1992	SI units and recommendations for the use of their multiples and of certain other units	-	-
ISO 2859-1	- <sup>1)</sup>	Sampling procedures for inspection by attributes - Part 1: Sampling schemes indexed by acceptance quality limit (AQL) for lot-by-lot inspection	-	-

<sup>1)</sup> Undated reference.

<sup>2)</sup> Valid edition at date of issue.

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<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
ISO 2859-10	- <sup>1)</sup>	Sampling procedures for inspection by attributes - Part 10: Introduction to the ISO 2859 series of standards for sampling for inspection by attributes	-	-
ISO 3534-2	- <sup>1)</sup>	Statistics - Vocabulary and symbols - Part 2: Applied statistics	-	-

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**PLASMA DISPLAY PANELS –****Part 5: Generic specification**

## FOREWORD

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International Standard IEC 61988-5 has been prepared by IEC technical committee 110: Flat panel display devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
110/182/FDIS	110/191/RVD

Full information on the voting for the approval on this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 61988 series, under the general title *Plasma display panels*, can be found on the IEC website.

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The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

## PLASMA DISPLAY PANELS –

### Part 5: Generic specification

#### 1 Scope

This generic specification for plasma display panels specifies general procedures for quality assessment to be used in the IECQ-CECC system and establishes general principles for describing and testing of electrical, optical, mechanical and environmental characteristics.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050 (all parts), *International electrotechnical vocabulary*

IEC 60410:1973, *Sampling plans and procedures for inspection by attributes*

IEC 60617, *Graphical symbols for diagrams*

IEC 60747-1, *Semiconductor devices – Part 1: General*

IEC 61988-1, *Plasma display panels – Part 1: Terminology and letter symbols*

IEC 61988-2-1, *Plasma display panels – Part 2-1: Measuring methods – Optical*

IEC 61988-2-2, *Plasma display panels – Part 2-2: Measuring methods – Optoelectrical*

IEC 61988-3-1, *Plasma display panels – Part 3-1: Mechanical interface*

IEC 61988-4, *Plasma display panels – Part 4: Climatic and mechanical testing methods*

IECQ 01, *IEC Quality Assessment System for Electronic components (IECQ) – Basic Rules*

QC 001002 (all parts), *IEC Quality Assessment System for Electronic components (IECQ) – Rules of Procedure*

ISO 1000:1992, *SI units and recommendations for the use of their multiples and of certain other units*

ISO 2859-1, *Sampling procedures for inspection by attributes – Part 1: Sampling schemes indexed by acceptance quality limit (AQL) for lot-by-lot inspection*

ISO 2859-10, *Sampling procedures for inspection by attributes – Part 10: Introduction to the ISO 2859 series of standards for sampling for inspection by attributes*

ISO 3534-2, *Statistics – Vocabulary and symbols – Part 2: Applied statistics*

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